

Refine Search

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L2 and (identif\$4 near5 processor)	12

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L3

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*DB=PGPB; PLUR=YES; OP=OR*L3 L2 and (identif\$4 near5 processor)12 L3L2 L1 and (writ\$3 near15 interrupt)41 L2L1 ("data structure" or data) near10 event near10 identif\$42865 L1

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
L3 and (identif\$4 near3 processor)	20

Database:

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L4

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DB=PGPB,USPT,USOC; PLUR=YES; OP=OR

L4 L3 and (identif\$4 near3 processor)
20 L4
L3 L2 and (writ\$3 near15 interrupt)
118 L3
L2 ("data structure" or data) near10 event near10 identif\$4
5193 L2

DB=DWPI; PLUR=YES; OP=OR

L1 ("data structure" or data) near10 event near10 identif\$4
474 L1

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
L3 and (identif\$4 near3 processor)	0

Database:

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Search:

L5

Search History

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result set

*DB=EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR*L5 L3 and (identif\$4 near3 processor)

0

L5*DB=PGPB,USPT,USOC; PLUR=YES; OP=OR*L4 L3 and (identif\$4 near3 processor)

20

L4L3 L2 and (writ\$3 near15 interrupt)

118

L3L2 ("data structure" or data) near10 event near10 identif\$4

5193

L2*DB=DWPI; PLUR=YES; OP=OR*L1 ("data structure" or data) near10 event near10 identif\$4

474

L1

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
(709/253 710/260 710/261 710/262 710/263 710/264 710/265 710/266 710/267 710/268 710/269 710/48 710/50 710/73 712/25 719/318).ccls.	3622

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Search:

L6

Refine Search

Recall Text

Clear

Interrupt

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result set

DB=PGPB,USPT,USOC; PLUR=YES; OP=OR

L6 710/260-269,48,50,73;719/318;709/253;712/25.ccls.

3622 L6

DB=EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR

L5 L3 and (identif\$4 near3 processor)

0 L5

DB=PGPB,USPT,USOC; PLUR=YES; OP=OR

L4 L3 and (identif\$4 near3 processor)

20 L4

L3 L2 and (writ\$3 near15 interrupt)

118 L3

L2 ("data structure" or data) near10 event near10 identif\$4

5193 L2

DB=DWPI; PLUR=YES; OP=OR

L1 ("data structure" or data) near10 event near10 identif\$4

474 L1

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
L4 or L7	30

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Search:

L8

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Set Name Query

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result set

DB=PGPB,USPT,USOC; PLUR=YES; OP=OR

L8 l4 or L7

30 L8

L7 l3 and L6

12 L7

L6 710/260-269,48,50,73;719/318;709/253;712/25.ccls.

3622 L6

DB=EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR

L5 L3 and (identif\$4 near3 processor)

0 L5

DB=PGPB,USPT,USOC; PLUR=YES; OP=OR

L4 L3 and (identif\$4 near3 processor)

20 L4

L3 L2 and (writ\$3 near15 interrupt)

118 L3

L2 ("data structure" or data) near10 event near10 identif\$4

5193 L2

DB=DWPI; PLUR=YES; OP=OR

L1 ("data structure" or data) near10 event near10 identif\$4

474 L1

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
L8 and (generat\$3 near10 interrupt near10 vector)	2

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Search:

L10

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Set Name Query
 side by side

Hit Count Set Name
 result set

DB=PGPB,USPT,USOC; PLUR=YES; OP=OR

<u>L10</u>	L8 and (generat\$3 near10 interrupt near10 vector)	2	<u>L10</u>
<u>L9</u>	L8 and (generat\$3 near5 interrupt)	26	<u>L9</u>
<u>L8</u>	L4 or L7	30	<u>L8</u>
<u>L7</u>	L3 and L6	12	<u>L7</u>
<u>L6</u>	710/260-269,48,50,73;719/318;709/253;712/25.ccls.	3622	<u>L6</u>

DB=EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR

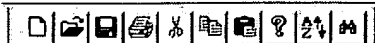
<u>L5</u>	L3 and (identif\$4 near3 processor)	0	<u>L5</u>
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DB=PGPB,USPT,USOC; PLUR=YES; OP=OR

<u>L4</u>	L3 and (identif\$4 near3 processor)	20	<u>L4</u>
<u>L3</u>	L2 and (writ\$3 near15 interrupt)	118	<u>L3</u>
<u>L2</u>	("data structure" or data) near10 event near10 identif\$4	5193	<u>L2</u>

DB=DWPI; PLUR=YES; OP=OR

<u>L1</u>	("data structure" or data) near10 event near10 identif\$4	474	<u>L1</u>
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L1: (126) ((data adj1 stru

L2: (4) l1 and (writ\$3 nea

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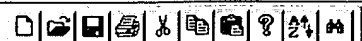
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BRS form IS&R form Image Text HTML

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1	BRS	L1	126	((data adj1 structure) or data) near10 event near10	USPAT	2006/10/05 15:12			
2	BRS	L2	4	l1 and (writ\$3 near15 interrupt)	USPAT	2006/10/05 15:13			



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L1: (126) ((data adj1 stru

L2: (4) l1 and (writ\$3 nea

Failed

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l1 and (writ\$3 near15 interrupt)

BRS form IS&R form Image Text HTML

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	R
1	<input type="checkbox"/>	<input type="checkbox"/>	US 6804631 B2	20041012	18	Event data acquisition	702/187	714/47	
2	<input type="checkbox"/>	<input type="checkbox"/>	US 5941964 A	19990824	11	Bridge buffer management by bridge interception of	710/100		
3	<input type="checkbox"/>	<input type="checkbox"/>	US 5878216 A	19990302	15	System and method for controlling a slave	709/208	709/210	
4	<input type="checkbox"/>	<input type="checkbox"/>	US 5471618 A	19951128	14	System for classifying input/output events for	710/19	340/3.51; 340/825.52;	


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» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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- ☐ 1. **Characteristics of single-event upsets in a fabric switch (AD8151)**
 Buchner, S.; Carls, M.A.; McMorro, D.; Hak Kim; Marshall, P.W.; LaBel, K.A.;
[Nuclear Science, IEEE Transactions on](#)
 Volume 51, Issue 5, Part 3, Oct. 2004 Page(s):2840 - 2845
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- ☐ 4. **GTO driving and protection technique with status monitoring**
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- ☐ 6. **Utilization of time varying event-based customer interruption cost load schemes**
Wangdee, W.; Billinton, R.;
[Probabilistic Methods Applied to Power Systems, 2004 International Conference](#)
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- ☐ 7. **Current-limiting inductors used in capacitor bank applications and their i current interruption**
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- ☐ 8. **An RFID-based multi-service system for supporting conference events**
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Digital Object Identifier 10.1109/AMT.2005.1505390
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Yanmei Li; Dongmei Li; Zhihua Wang;
[National Aerospace and Electronics Conference, 2000. NAECON 2000. Proce](#)
[IEEE 2000](#)
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Utilization of time varying event-based customer interruption cost load shedding schemes

Wangdee, W. Billinton, R.

This paper appears in: Probabilistic Methods Applied to Power Systems, 2004 International Conference on

Publication Date: 12-16 Sept. 2004

On page(s): 769 - 775

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Abstract

Load curtailments occurring under emergency conditions can have significant monetary impacts on the system customers. Customer satisfaction is becoming increasingly important in the new deregulated electric utility environment, and the customers in some jurisdictions are beginning to receive monetary compensation for power supply failures. Minimizing the customer interruption costs associated with a load curtailment event is an important factor in maintaining customer satisfaction. Customer interruption costs depend on many factors such as the customer types **interrupted**, the actual load demand at the time of the outage, the duration of the outage, the time of day and the day in which the outage occurs. This paper focuses on incorporating these interruption cost factors in a load shedding strategy. The load shedding algorithm was developed using an approximate event-based customer interruption cost evaluation technique to **identify** and determine the priority of the distribution feeders on a given bus during an emergency. The developed algorithm incorporates a time dependent feeder cost priority index (FCP). The optimum load shedding set determined using the FCP is a feeder or group of feeders that meet a capacity deficiency, and result in the lowest customer interruption cost for the specified emergency situation. This paper illustrates the algorithm development for a load shedding scheme and demonstrates the utilization of the technique on a sample load bus.

Index Terms
Inspec

Controlled Indexing

cost reduction customer satisfaction electricity supply industry deregulation load shedding
power distribution economics power distribution faults

Non-controlled Indexing

cost evaluation technique customer interruption cost minimization customer satisfaction
deregulated electric utility distribution feeders event-based customer interruption feeder
cost priority index load bus load curtailment event load demand load shedding schemes
power supply failures

Author Keywords

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